

# PMV30UN

μTrenchMOS™ ultra low level FET

Rev. 01 — 25 June 2003

Product data

## 1. Product profile

### 1.1 Description

N-channel enhancement mode field-effect transistor in a plastic package using TrenchMOS™ technology.

Product availability:

PMV30UN in SOT23.

### 1.2 Features

- Surface mount package
- Fast switching.

### 1.3 Applications

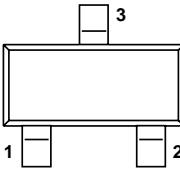
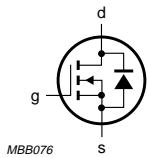
- Battery management
- High-speed switches.

### 1.4 Quick reference data

- $V_{DS} \leq 20$  V
- $I_D \leq 5.7$  A
- $P_{tot} \leq 1.9$  W
- $R_{DSon} \leq 36$  mΩ

## 2. Pinning information

Table 1: Pinning - SOT23 simplified outline and symbol

Pin	Description	Simplified outline	Symbol
1	gate (g)		
2	source (s)		
3	drain (d)	 Top view MSB003	 MBB076



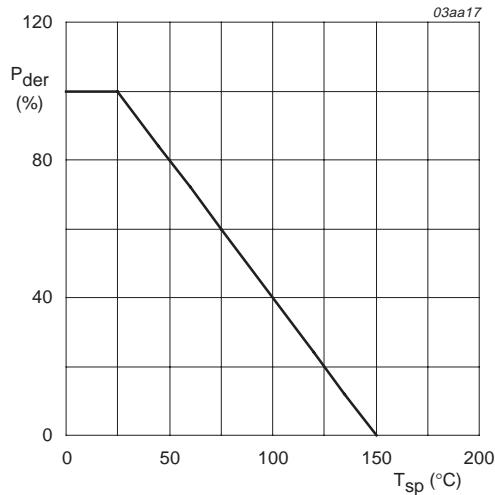
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### 3. Limiting values

**Table 2: Limiting values**

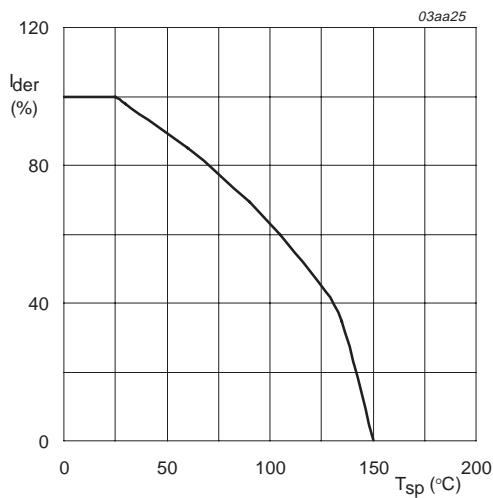
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage (DC)	$25^{\circ}\text{C} \leq T_j \leq 150^{\circ}\text{C}$	-	20	V
$V_{DGR}$	drain-gate voltage (DC)	$25^{\circ}\text{C} \leq T_j \leq 150^{\circ}\text{C}; R_{GS} = 20\text{ k}\Omega$	-	20	V
$V_{GS}$	gate-source voltage (DC)		-	$\pm 8$	V
$I_D$	drain current (DC)	$T_{sp} = 25^{\circ}\text{C}; V_{GS} = 4.5\text{ V}; \text{Figure 2 and 3}$	-	5.7	A
		$T_{sp} = 100^{\circ}\text{C}; V_{GS} = 4.5\text{ V}; \text{Figure 2}$	-	3.65	A
$I_{DM}$	peak drain current	$T_{sp} = 25^{\circ}\text{C}; \text{pulsed}; t_p \leq 10\text{ }\mu\text{s}; \text{Figure 3}$	-	23.1	A
$P_{tot}$	total power dissipation	$T_{sp} = 25^{\circ}\text{C}; \text{Figure 1}$	-	1.9	W
$T_{stg}$	storage temperature		-55	+150	$^{\circ}\text{C}$
$T_j$	junction temperature		-55	+150	$^{\circ}\text{C}$
<b>Source-drain diode</b>					
$I_S$	source (diode forward) current (DC)	$T_{sp} = 25^{\circ}\text{C}$	-	1.6	A
$I_{SM}$	peak source (diode forward) current	$T_{sp} = 25^{\circ}\text{C}; \text{pulsed}; t_p \leq 10\text{ }\mu\text{s}$	-	6.4	A



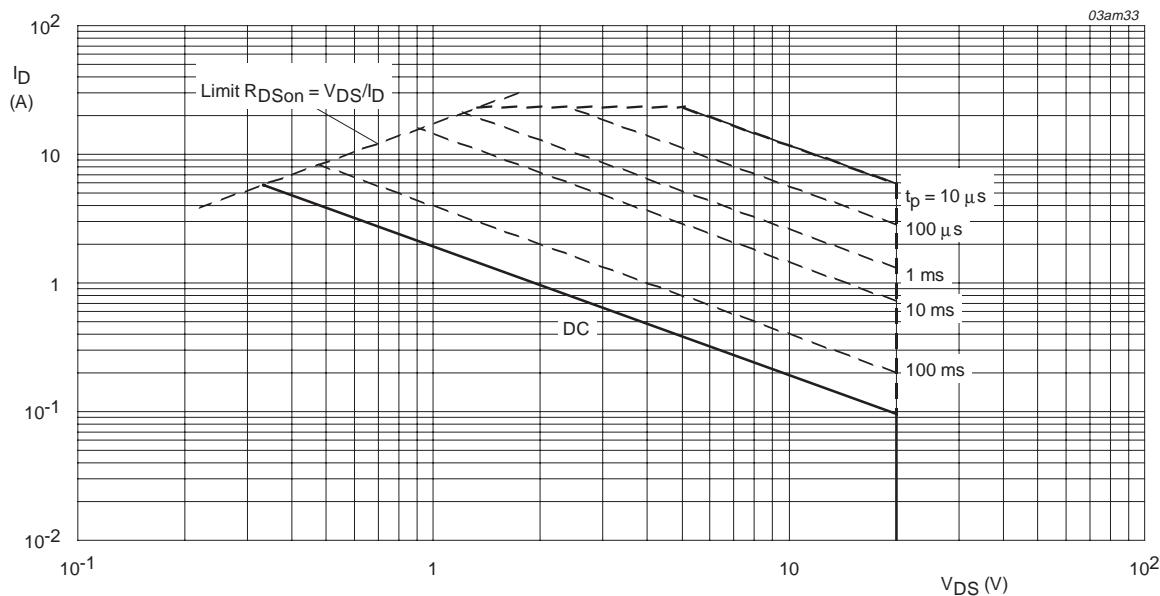
$$P_{der} = \frac{P_{tot}}{P_{tot}(25^{\circ}C)} \times 100\%$$

**Fig 1. Normalized total power dissipation as a function of solder point temperature.**



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

**Fig 2. Normalized continuous drain current as a function of solder point temperature.**



$T_{sp} = 25^{\circ}C$ ;  $I_{DM}$  is single pulse;  $V_{GS} = 4.5 V$

**Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.**

## 4. Thermal characteristics

Table 3: Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point	Figure 4	-	-	65	K/W

### 4.1 Transient thermal impedance

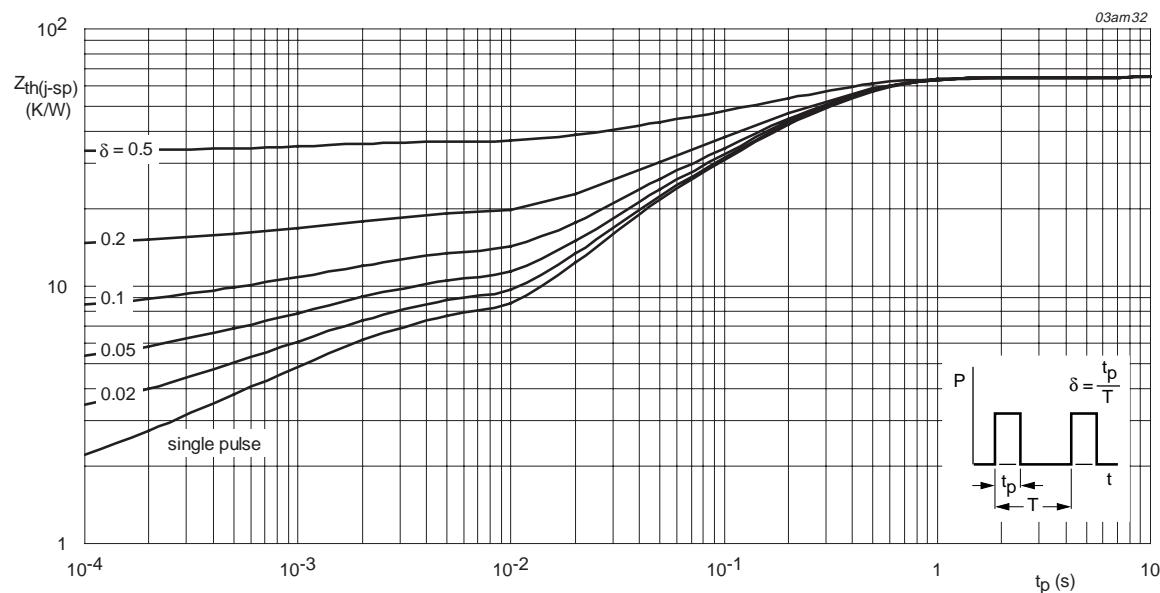
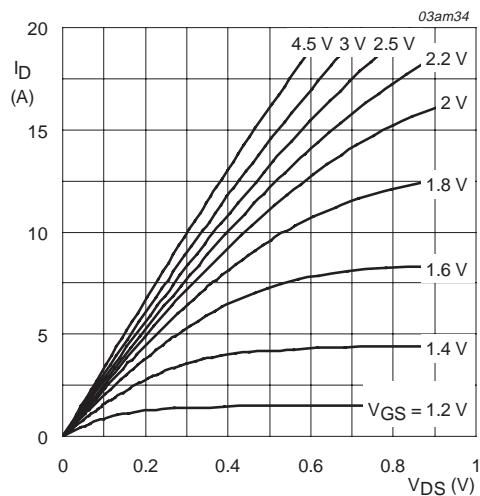


Fig 4. Transient thermal impedance from junction to solder point as a function of pulse duration.

## 5. Characteristics

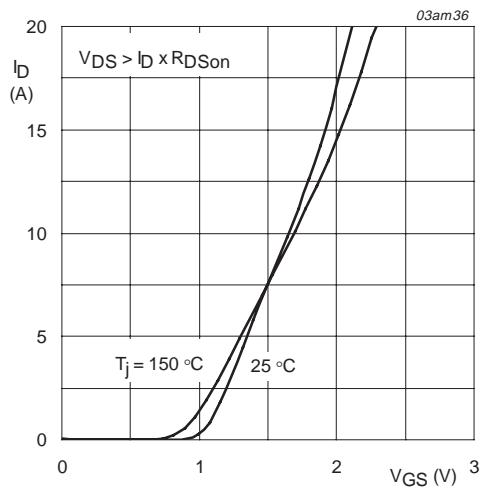
**Table 4: Characteristics** $T_j = 25^\circ\text{C}$  unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static characteristics</b>						
$V_{(\text{BR})\text{DSS}}$	drain-source breakdown voltage	$I_D = 250 \mu\text{A}; V_{GS} = 0 \text{ V}$				
		$T_j = 25^\circ\text{C}$	20	-	-	V
		$T_j = -55^\circ\text{C}$	18	-	-	V
$V_{GS(\text{th})}$	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}$ ; Figure 9				
		$T_j = 25^\circ\text{C}$	0.45	0.7	-	V
		$T_j = 150^\circ\text{C}$	0.25	0.4	-	V
$I_{DSS}$	drain-source leakage current	$V_{DS} = 20 \text{ V}; V_{GS} = 0 \text{ V}$				
		$T_j = 25^\circ\text{C}$	-	-	1	$\mu\text{A}$
		$T_j = 150^\circ\text{C}$	-	-	100	$\mu\text{A}$
$I_{GSS}$	gate-source leakage current	$V_{GS} = \pm 8 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nA
$R_{D\text{Son}}$	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 2 \text{ A}$ ; Figure 7 and 8				
		$T_j = 25^\circ\text{C}$	-	30	36	$\text{m}\Omega$
		$T_j = 150^\circ\text{C}$	-	48	57.6	$\text{m}\Omega$
		$V_{GS} = 2.5 \text{ V}; I_D = 1.5 \text{ A}$ ; Figure 7 and 8	-	36	43	$\text{m}\Omega$
		$V_{GS} = 1.8 \text{ V}; I_D = 1 \text{ A}$ ; Figure 7 and 8	-	44	63	$\text{m}\Omega$
<b>Dynamic characteristics</b>						
$Q_{g(\text{tot})}$	total gate charge	$I_D = 5 \text{ A}; V_{DD} = 10 \text{ V}; V_{GS} = 4.5 \text{ V}$ ; Figure 13	-	7.4	-	nC
$Q_{gs}$	gate-source charge		-	1.2	-	nC
$Q_{gd}$	gate-drain (Miller) charge		-	1.8	-	nC
$C_{iss}$	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 20 \text{ V}; f = 1 \text{ MHz}$ ; Figure 11	-	460	-	pF
$C_{oss}$	output capacitance		-	100	-	pF
$C_{rss}$	reverse transfer capacitance		-	70	-	pF
$t_{d(\text{on})}$	turn-on delay time	$V_{DD} = 10 \text{ V}; R_L = 10 \Omega; V_{GS} = 4.5 \text{ V}; R_G = 6 \Omega$	-	7	-	ns
$t_r$	rise time		-	13	-	ns
$t_{d(\text{off})}$	turn-off delay time		-	53	-	ns
$t_f$	fall time		-	13	-	ns
<b>Source-drain diode</b>						
$V_{SD}$	source-drain (diode forward) voltage	$I_S = 1.7 \text{ A}; V_{GS} = 0 \text{ V}$ ; Figure 12	-	0.81	1.2	V



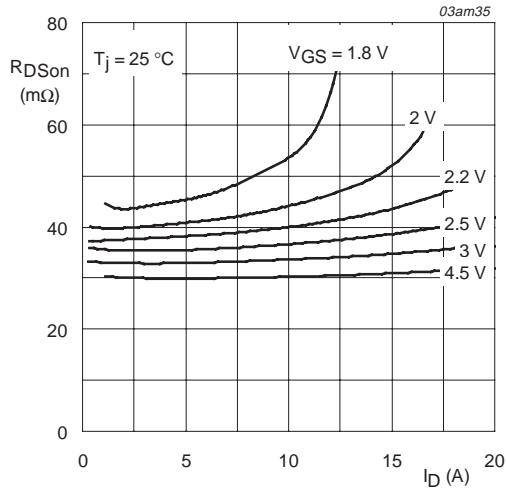
$T_j = 25^\circ\text{C}$

**Fig 5.** Output characteristics: drain current as a function of drain-source voltage; typical values.



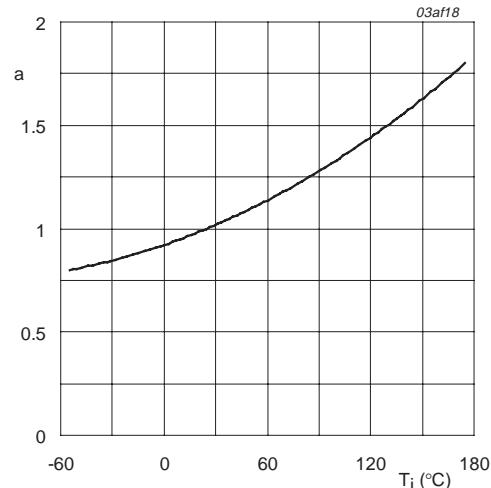
$T_j = 25^\circ\text{C}$  and  $150^\circ\text{C}$ ;  $V_{DS} > I_D \times R_{DSon}$

**Fig 6.** Transfer characteristics: drain current as a function of gate-source voltage; typical values.



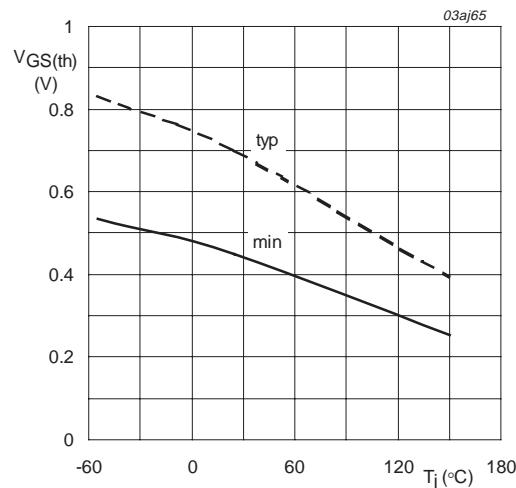
$T_j = 25^\circ\text{C}$

**Fig 7.** Drain-source on-state resistance as a function of drain current; typical values.



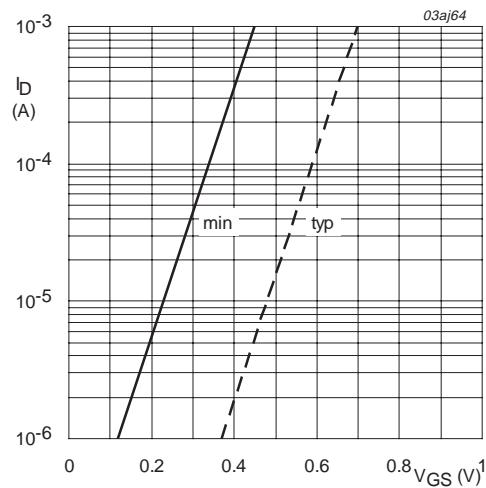
$$a = \frac{R_{DSon}}{R_{DSon}(25^\circ\text{C})}$$

**Fig 8.** Normalized drain source on-state resistance factor as a function of junction temperature.



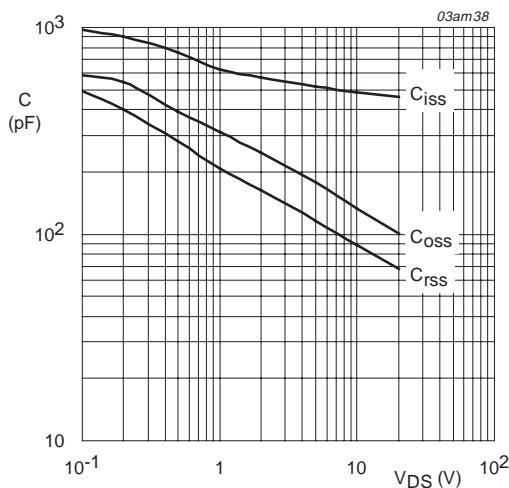
$I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

**Fig 9. Gate-source threshold voltage as a function of junction temperature.**



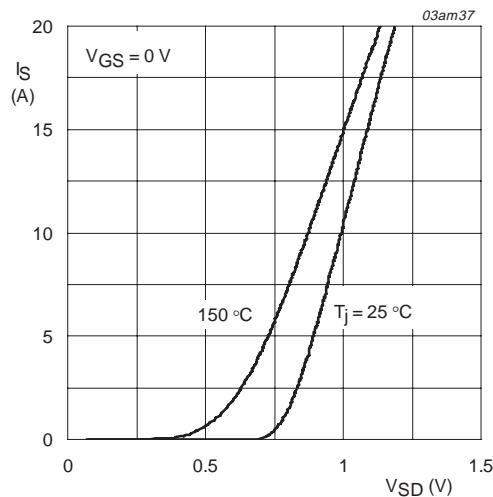
$T_j = 25 \text{ }^\circ\text{C}; V_{DS} = 5 \text{ V}$

**Fig 10. Sub-threshold drain current as a function of gate-source voltage.**



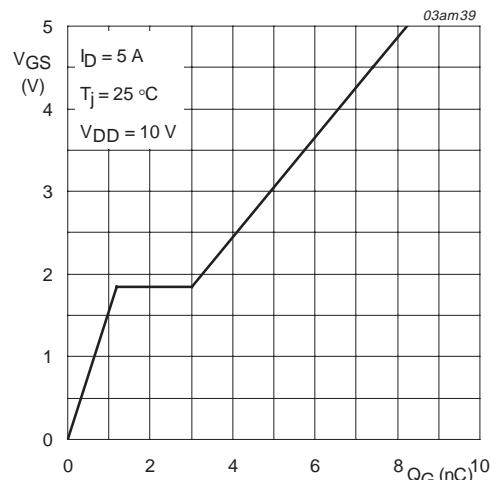
$V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$

**Fig 11. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.**



$T_j = 25^\circ\text{C}$  and  $150^\circ\text{C}$ ;  $V_{GS} = 0 \text{ V}$

**Fig 12. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.**



$I_D = 5 \text{ A}; V_{DD} = 10 \text{ V}$

**Fig 13. Gate-source voltage as a function of gate charge; typical values.**

## 6. Package outline

Plastic surface mounted package; 3 leads

SOT23

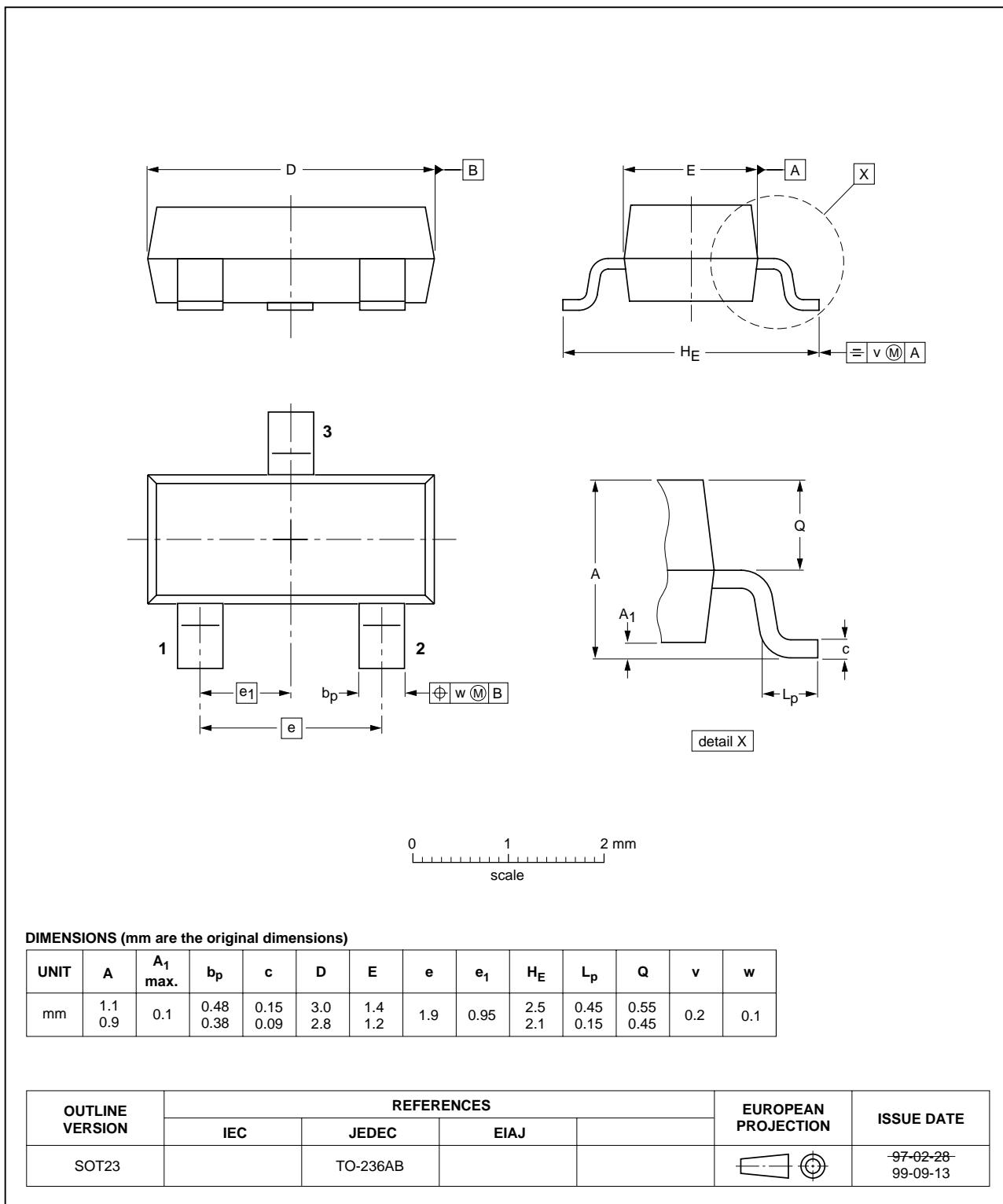


Fig 14. SOT23.

## 7. Revision history

**Table 5: Revision history**

Rev	Date	CPCN	Description
01	20030625	-	Product data (9397 750 11569)

## 8. Data sheet status

Level	Data sheet status <sup>[1]</sup>	Product status <sup>[2][3]</sup>	Definition
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
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For sales office addresses, send e-mail to: [sales.addresses@www.semiconductors.philips.com](mailto:sales.addresses@www.semiconductors.philips.com).

Fax: +31 40 27 24825

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